

GOVERNMENT OF INDIA ELECTRONICS REGIONAL TEST LABORATORY (WEST)

MINISTRY OF ELECTRONICS & INFORMATION TECHNOLOGY, STOC DIRECTORATE.

COVER SHEET

TESTING REPORT

REPORT NO.:ERTL(W) 2018 SAF 36

DATE OF ISSUE: 28 SEP 2018

PAGE 01 OF REPORT

TITLE: TESTING OF LAB GROWN DIAMOND DETECTOR

1.1 Service Request No.and Date:

20180391 , 23-AUG-18

1.2 Name and Address of Customer:

M/s. AROTEK SCIENTIFIC INSTRUMENTS PVT.LTD

SHOP NO.-8, BLDG, NO-5

AMRUT AANGAN, PHASE II, PARSIK NAGAR, KALWA (WEST)

THANE-400605

THANE

1.3 Report in the Name of:

M/s. AROTEK SCIENTIFIC INSTRUMENTS PVT.LTD

SHOP NO.-8, BLDG. NO-5

AMRUT AANGAN, PHASE II, PARSIK NAGAR, KALWA (WEST

THANE-400605

THANE

Report Released By

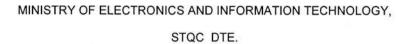
J L N MURTY V R CHAVAN

Customer Service Cell



GOVERNMENT OF INDIA

ELECTRONICS REGIONAL TEST LABORATORY (WEST)





REPORT NO.: ERTL (W)/ 2018SAF36

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TITLE: TESTING OF LAB GROWN DIAMOND DETECTOR	DATE OF ISSUE
	28-Sept-2018

1.0 SCOPE:

1.1	Service request no and Date	As per cover sheet As per cover sheet			
1.2	Name and address of Customer:				
1.3	Description & Identification of Test item(s)	Nomenclature :	LAB GROWN DIAMOND DETECTOR *		
		Manufacturer :	Manufacturer : AROTEK SCIENTIFIC INSTRUMENTS PVT Ltd *		
		Model/Type	Qchk Adc *		
		Sl. No. :	QCHKADC 00001 *		
		Quantity:	01		
1.4	Item(s) condition on receipt:	J/C Received	Sample Received	Test Completed	
	ок	24-08-2018	24-08-2018	20/09/2018	
1.5	Testing performed at :	At ERTL (W), Mumbai.			
1.6	Laboratory Ambient :	Temperature: (25 ± 3) °C; Humidity: (45 To 75) % RH			
1.7	Test Specification / Test Procedure used.	IEC 61010-1: (Edition 3.1) : 2017			
1.8	Major Equipments used and Traceability Details:				
SI. No.	Equipment Used	Uncertainty (Best Case)	Calibration Report Ref.	Valid up to	
1	Electrical Safety Analyzer	± 1.5 %	2017S&C565	07/12/2018	
2	41/2 Digital Multi-meter	± 0.12 %	2018S&C124 28/02/2019		
3	Digital Power Meter	± 0.04 %	2017S&C532 10/11/2018		
4	Hybride Temperature Recorder	±0.3 °C	2017TNP214	02/11/2018	

QSF 5.10.09 dated 01/01/2014

RELEASED BY

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^{*} As marked on test item.



Report No.: ERTL (W)/ 2018SAF36

TEST REPORT IEC 61010-1

Safety requirements for electrical equipment for measurement, control, and laboratory use Part 1: General requirements

Report Number.....: ERTL(W)/2018SAF36

Date of issue.....: 28-Sept-2018

Total number of pages: 95

Name of Testing Laboratory

preparing the Report ELECTRONICS REGIONAL TEST LABORATORY (WEST

Applicant's name AROTEK SCIENTIFIC INSTRUMENTS PVT.LTD.

Address...... Shop No. 8, Amrut Aangan, Phase-II, Building No. 5, Parsik

Nagar, Kalwa west, Thane-400605.

Test specification:

Standard: IEC 61010-1:2010, AMD1:2016 (Edition 3.1)

Test procedure: ERTL(W)/SAF/PROCEDURE

Non-standard test method: N/A

Test Report Form No.: IEC61010_1L

Test Report Form(s) Originator: VDE Testing and Certification Institute

Master TRF 2017-10-20

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General disclaimer:

The test results presented in this report relate only to the object tested.

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Report No.: ERTL (W)/ 2018SAF36

Test item description: LAB GROWN DIAMOND DETECTOR				
Trade Mark:	Nil			
Manufacturer:	AROTI	TEK SCIENTIFIC INSTRUMENTS PVT. LTD		
Model/Type reference:	Qchk A	Adc		
Ratings:	230/11	10 VAC, 0.5/0.8 A, 50/60 Hz,		
Responsible Testing Laboratory (as a	applicat	ole), testing procedure and tes	sting location(s):	
			•	
Testing location/ address	:	ELECTRONICS REGIONAL TEST LABORATORY (WEST) Opp SEEPZ, Plot F7&8, MIDC Marol Area, Andheri (E), Mumbai-93		
Tested by (name, function, signature):		Rahul Jagtap, Scientist 'B'	Que	
Checked by (name, function, signature	re):	Lata Gholap Scientist 'C'	Valadula	
Approved by (name, function, signature):		Vinod K Dhar, Scientist 'E'		

